

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/617,642	PARK ET AL.	
Examiner	Art Unit	_
Minh Dinh	2132	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
713/160,162 380/259-262,270,273-274,37,42-44,28 (text search only for all - see search history printout)	11/4/2006	MD 		
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) - see search history printout	11/4/2006	MD		
NPL (ACM, GOOGLE, IEEE)	11/4/2006	MD		
Inventor Name Search	11/4/2006	MD		